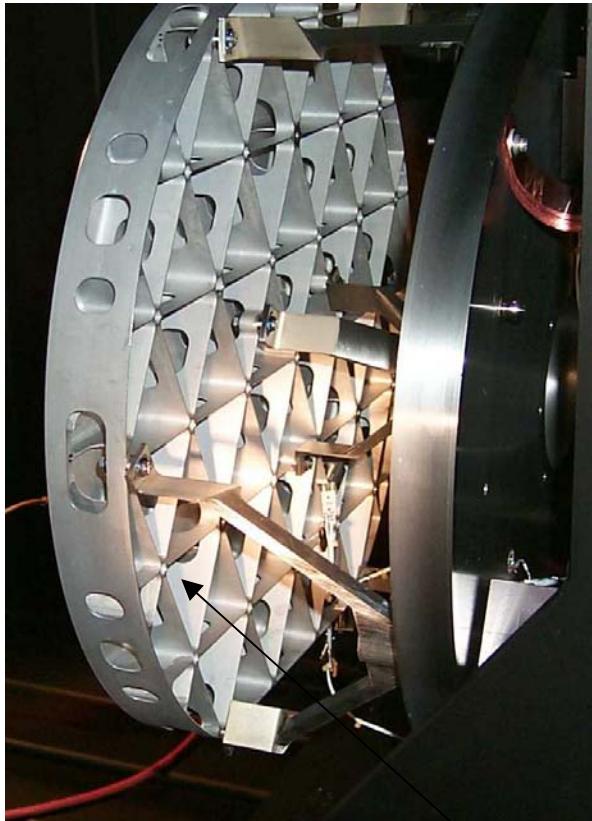




PREDICTING PRINT-THRU  
for the  
SUB-SCALE BERYLLIUM  
MIRROR DEMONSTRATOR  
(SBMD)

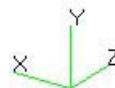


# SBMD

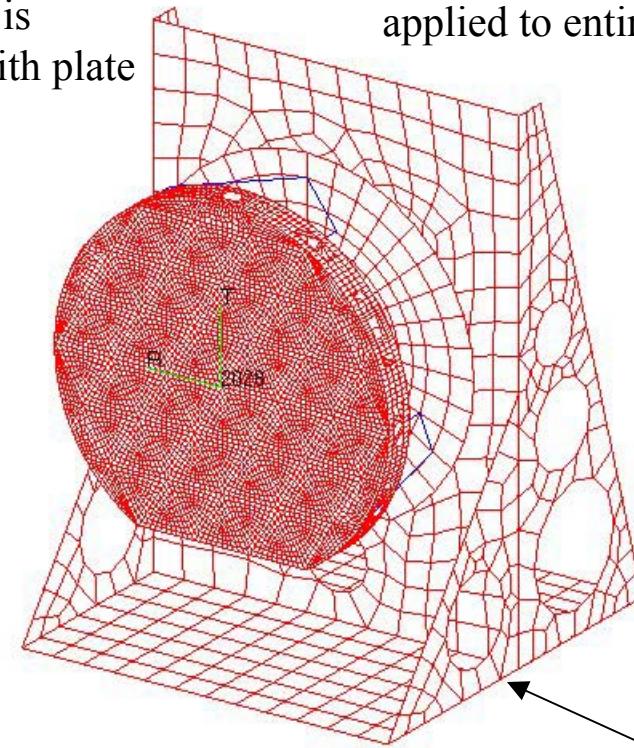


triangular  
pocket

Be O-30 mirror is represented with plate finite elements



NASTRAN model



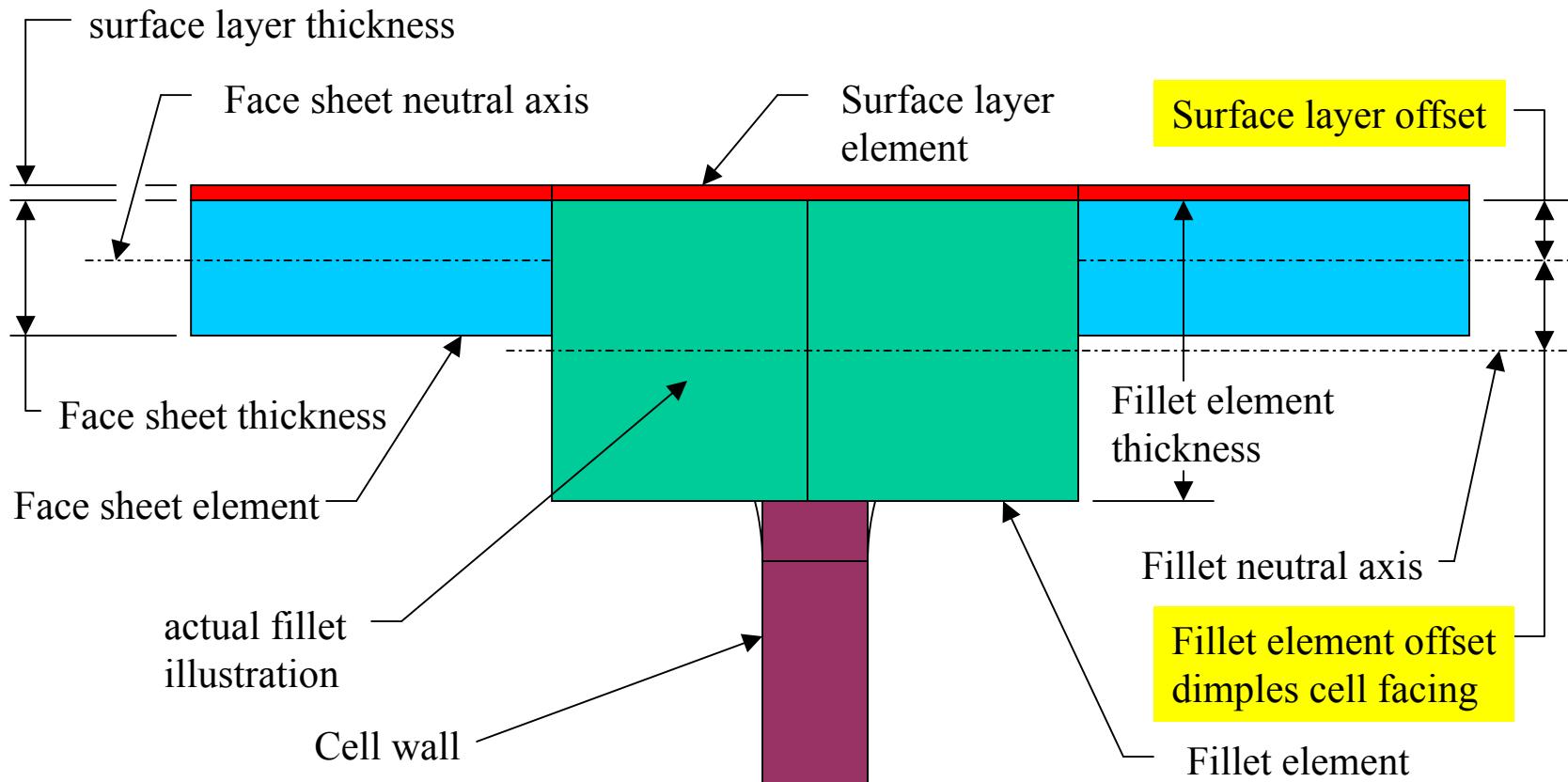
Thermal load of  $-263\text{ K}$   
uniform temperature change  
applied to entire model.



# SBMD Print-Thru Study

- Fillets between facesheet and cell walls were investigated.
- Thin surface layer (due to polishing) with different material properties was investigated.
- Individually neither produced print-thru.

# Finite Element Analysis Method



Face sheet/cell wall cross-section geometry and finite element representation

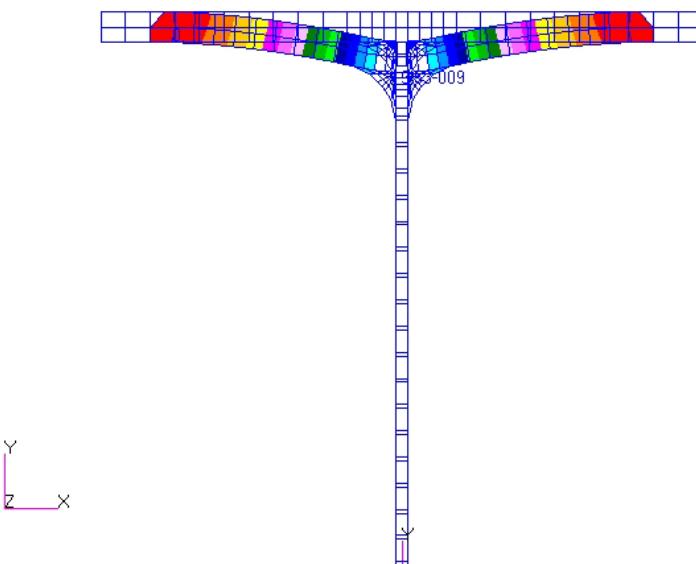


# Cross-section Model to Determine Fillet Element Thickness

MSC.Ptran 2000 r2 01-Apr-02 11:06:14

Fringe: 30K, Static Subcase\_5: Displacements, Translational-(NON-LAYERED) (YY)

Deform: 30K, Static Subcase\_5: Displacements, Translational



With as designed fillet, Y displacement (m)

6.5 mm thick (face sheet + fillet) rectangular fillet

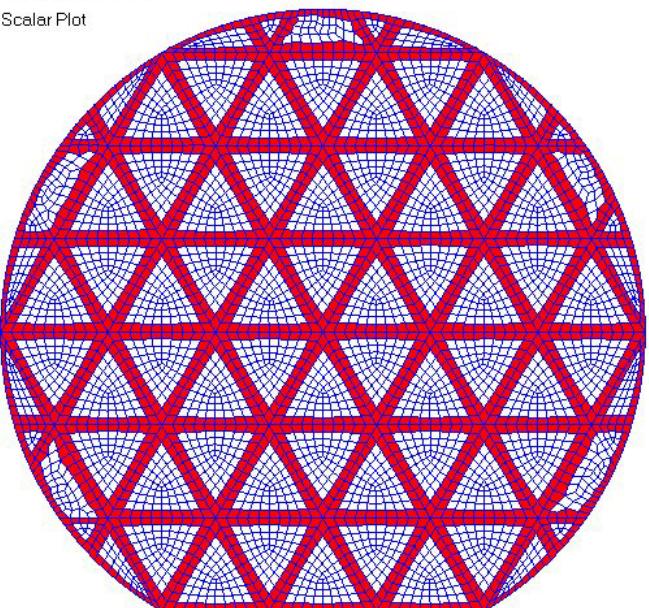
Cross-section model parameters: surface layer CTE = 0.513 ppm/K,  
surface layer thickness = 12.7 microns



# Fillet and Facesheet Finite Element Representation

MSC.Patran 2000 r2 26-Apr-02 13:28:03

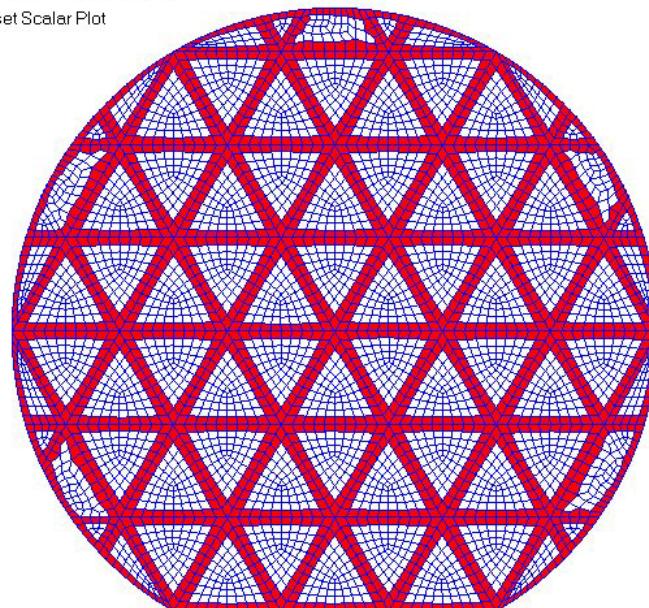
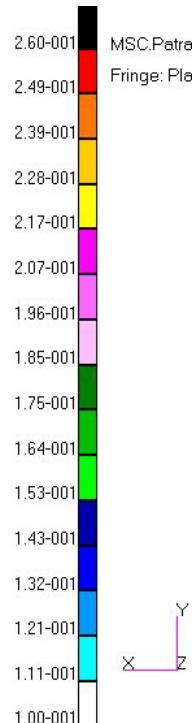
Fringe: Thickness Scalar Plot



Fillet and facesheet thickness (in)

MSC.Patran 2000 r2 17-May-02 10:18:18

Fringe: Plate Offset Scalar Plot

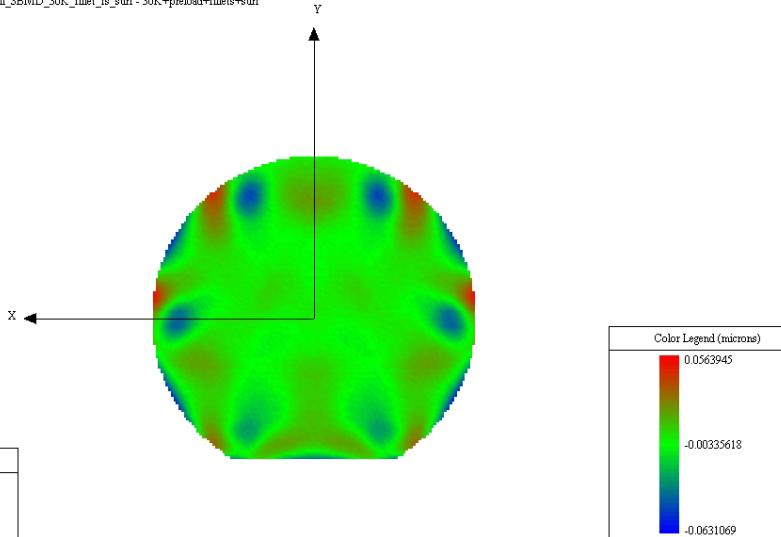


Fillet and facesheet offset (in)

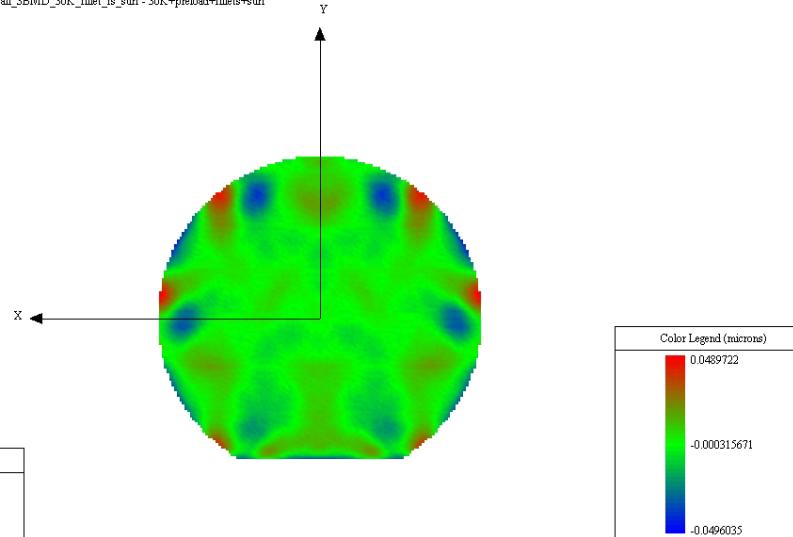
Thin surface layer not shown

# SBMD Print-Thru Prediction

Ball\_SBMD\_30K\_fillet\_fs\_surf - 30K+preload+fillets+surf



Ball\_SBMD\_30K\_fillet\_fs\_surf - 30K+preload+fillets+surf



Residual surface –43 wavescope Zernikes  
5.08  $\mu\text{m}$  surface layer thickness. Surface layer  
CTE same as face sheet.  
P-V 120 nm, RMS 13.1 nm

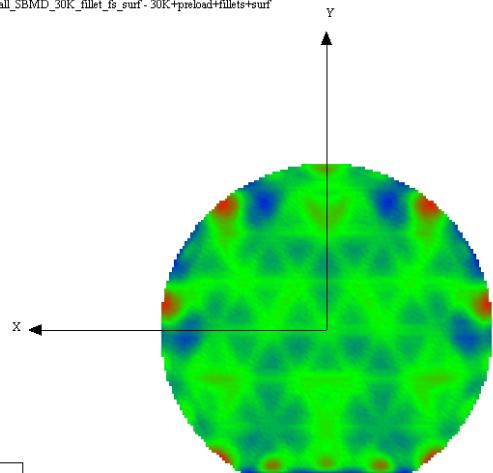
Residual surface –43 wavescope Zernikes  
5.08  $\mu\text{m}$  surface layer thickness. Surface layer  
CTE 10% larger than face sheet.  
P-V 99 nm, RMS 11.4 nm

Left plot shows result without surface layer CTE effect (no quilting).  
Quilting is beginning to appear in the right-hand plot.



# SBMD Print-Thru Prediction

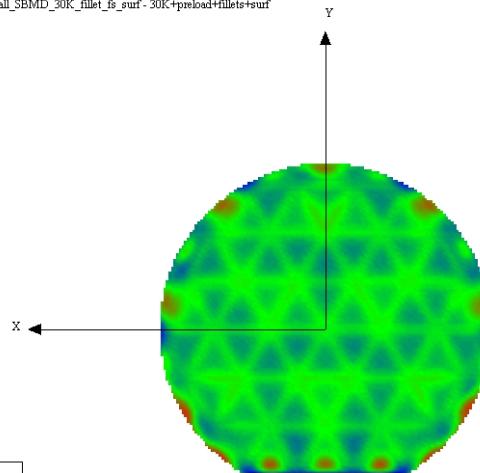
Ball\_SBMD\_30K\_fillet\_fs\_surf - 30K+preload+fillets+surf



Statistics (microns)	
Number of Groups:	1
Peak to Valley:	0.0885584
Deflection RMS:	0.00994683

Residual surface –43 wavescope Zernikes  
12.7  $\mu\text{m}$  surface layer thickness. Surface layer  
CTE 10% larger than face sheet.  
P-V 89 nm, RMS 9.9 nm

Ball\_SBMD\_30K\_fillet\_fs\_surf - 30K+preload+fillets+surf+surf



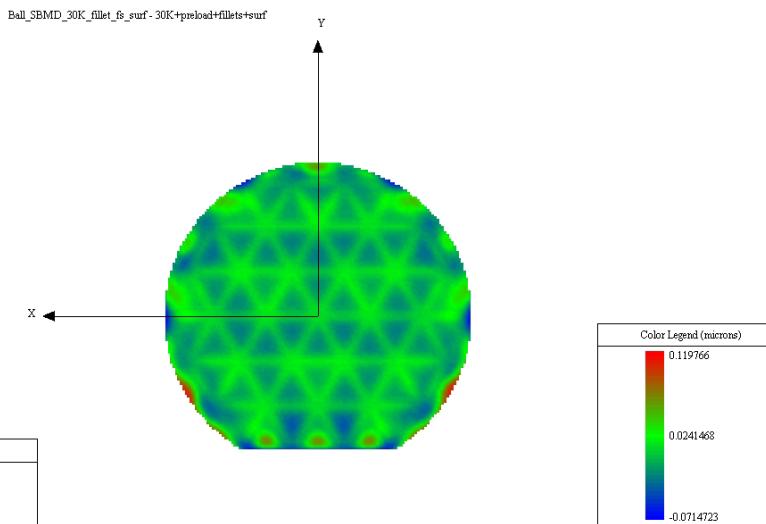
Statistics (microns)	
Number of Groups:	1
Peak to Valley:	0.120884
Deflection RMS:	0.0119331

Residual surface –43 wavescope Zernikes  
25.4  $\mu\text{m}$  surface layer thickness. Surface layer  
CTE 10% larger than face sheet.  
P-V 121 nm, RMS 11.9 nm

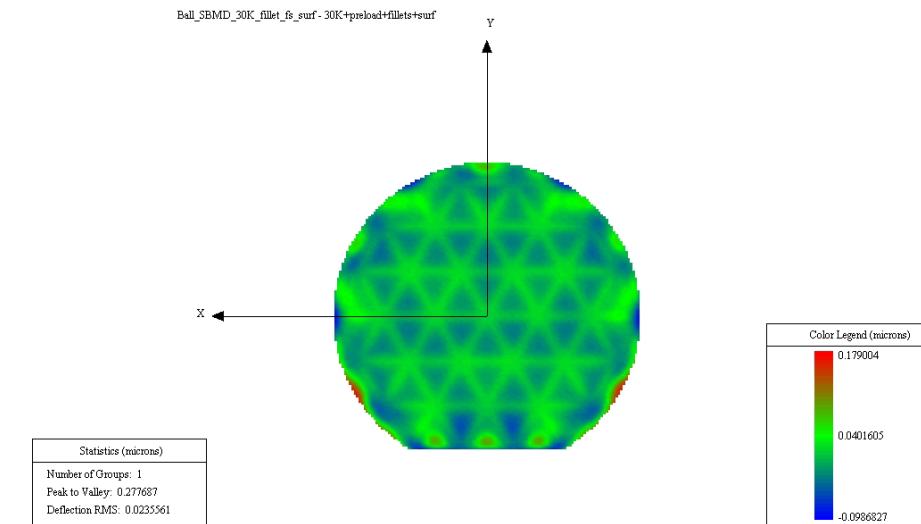
As the surface layer thickness increases print-thru becomes more pronounced.



# SBMD Print-Thru Prediction

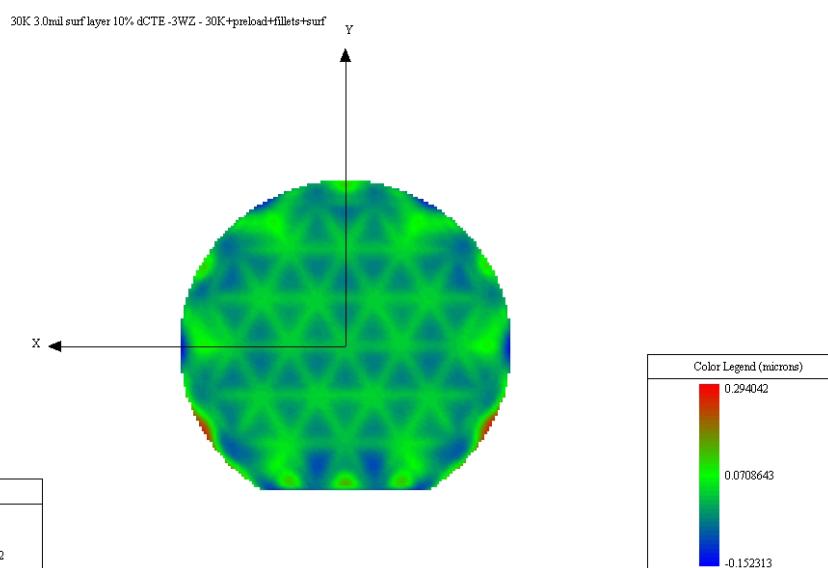


Residual surface –43 wavescope Zernikes  
38.1  $\mu\text{m}$  surface layer thickness. Surface layer  
CTE 10% larger than face sheet.  
P-V 191 nm, RMS 17.2 nm

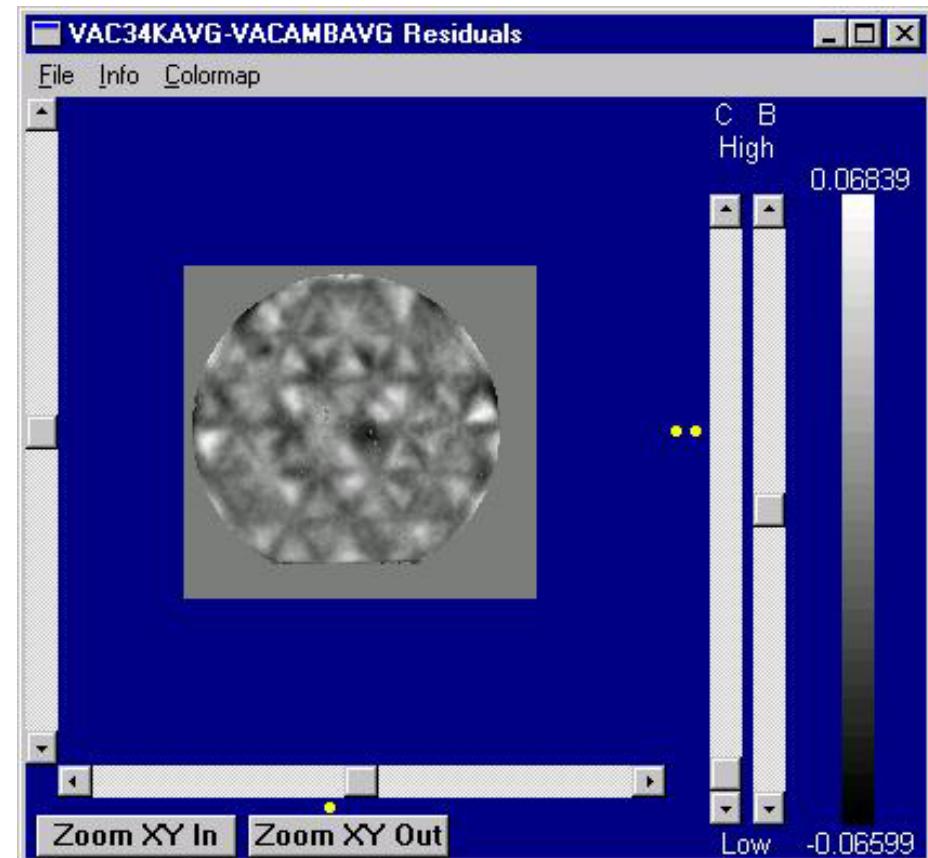


Residual surface –43 wavescope Zernikes  
50.8  $\mu\text{m}$  surface layer thickness. Surface layer  
CTE 10% larger than face sheet.  
P-V 278 nm, RMS 23.6 nm

# SBMD Print-Thru Prediction



Residual surface –43 wavescope Zernikes  
76.2  $\mu\text{m}$  surface layer thickness. Surface layer  
CTE 10% larger than face sheet.  
P-V 446 nm, RMS 36.9 nm

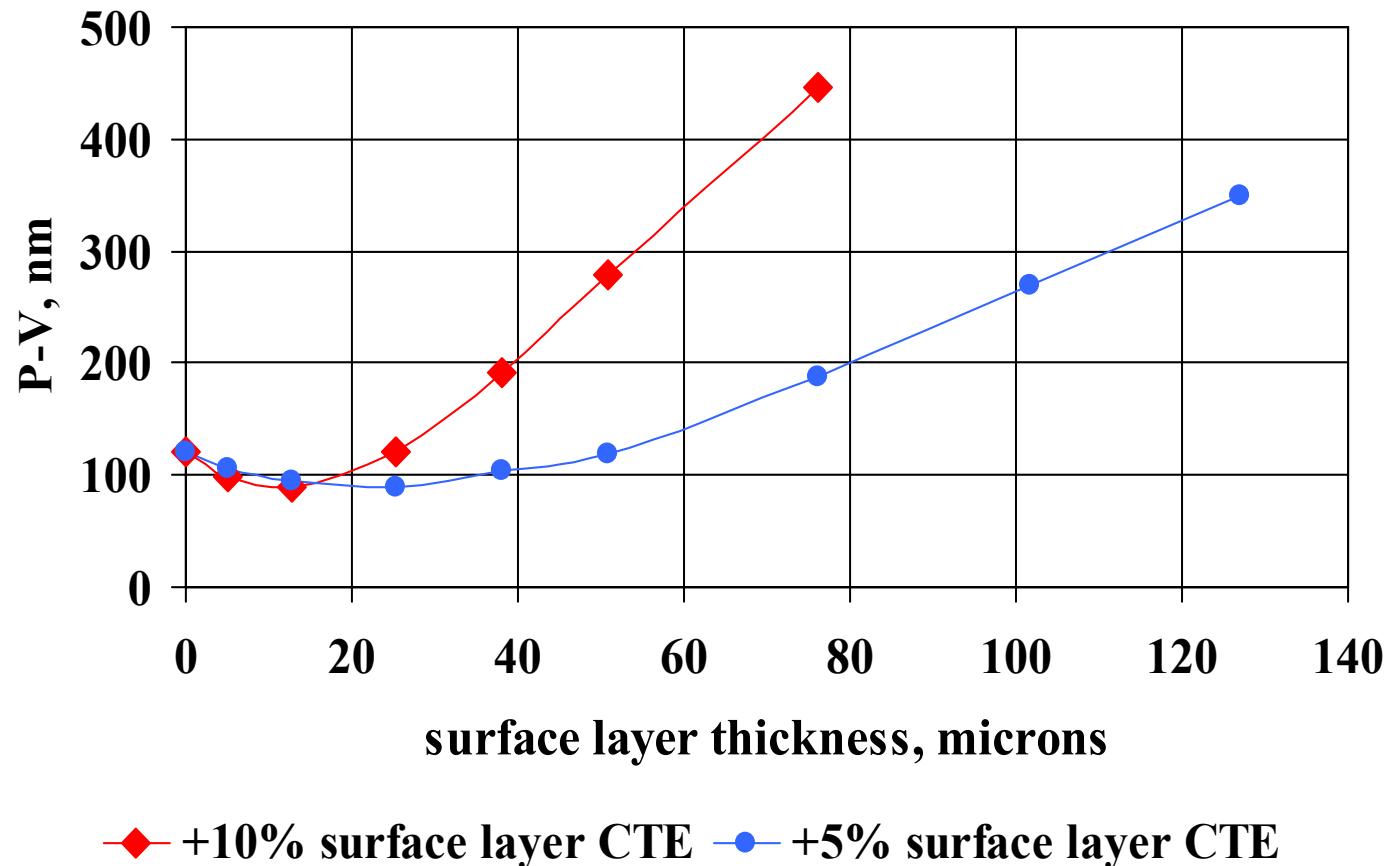


Measured data



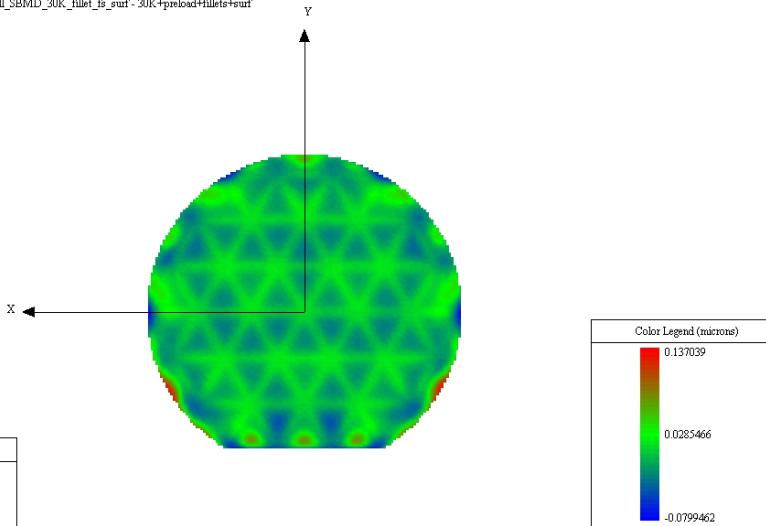
# P-V vs Surface Layer Thickness

## 43 Wavescope Zernikes Removed

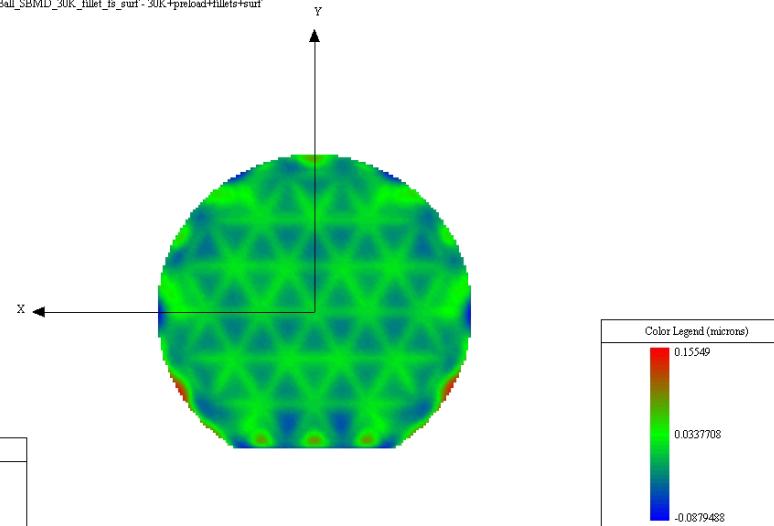


# Surface Layer Elastic Modulus Effect

Ball\_SBMD\_30K\_fillet\_fb\_surf - 30K+preload+fillets+surf



Ball\_SBMD\_30K\_fillet\_fb\_surf - 30K+preload+fillets+surf

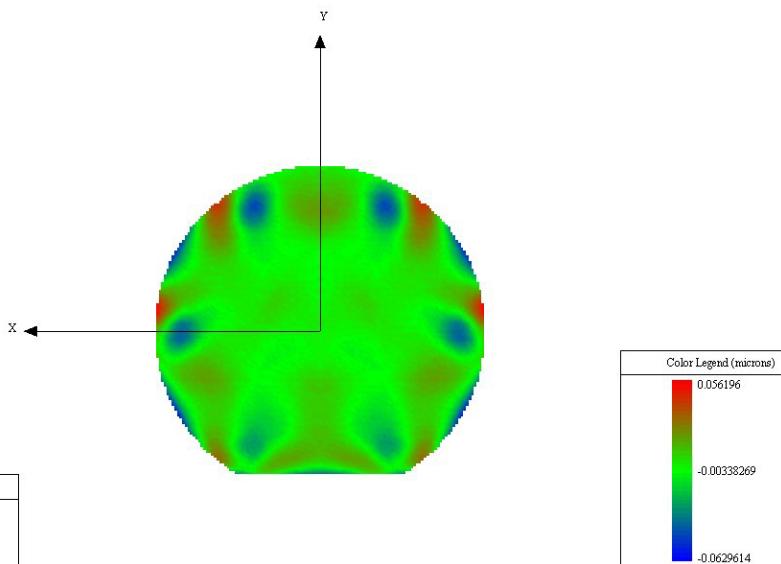


Residual surface –43 wavescope Zernikes  
38.1  $\mu\text{m}$  surface layer thickness. Surface layer  
CTE 10% larger than face sheet and 10% larger  
E modulus. P-V 217 nm, RMS 19.0 nm

Residual surface –43 wavescope Zernikes  
38.1  $\mu\text{m}$  surface layer thickness. Surface layer  
CTE 10% larger than face sheet and 20% larger  
E modulus. P-V 243 nm, RMS 21 nm

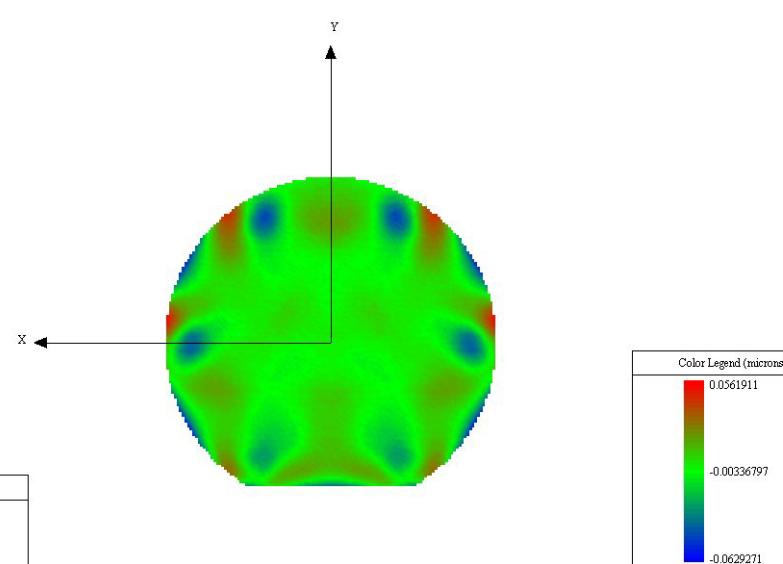
This shows that increasing the surface layer modulus E increases the quilting magnitude

# Surface Layer Elastic Modulus Effect



Residual surface -43 wavescope Zernikes  
12.7  $\mu\text{m}$  surface layer thickness. Surface layer  
E modulus 10% larger than face sheet and both  
have same CTE. P-V 120 nm, RMS 13.1 nm

These results indicate that a differential E modulus alone will not produce quilting.  
The differential CTE is necessary for quilting.



Residual surface -43 wavescope Zernikes  
12.7  $\mu\text{m}$  surface layer thickness. Surface layer  
E modulus 20% larger than face sheet and both  
have same CTE. P-V 120 nm, RMS 13.1 nm



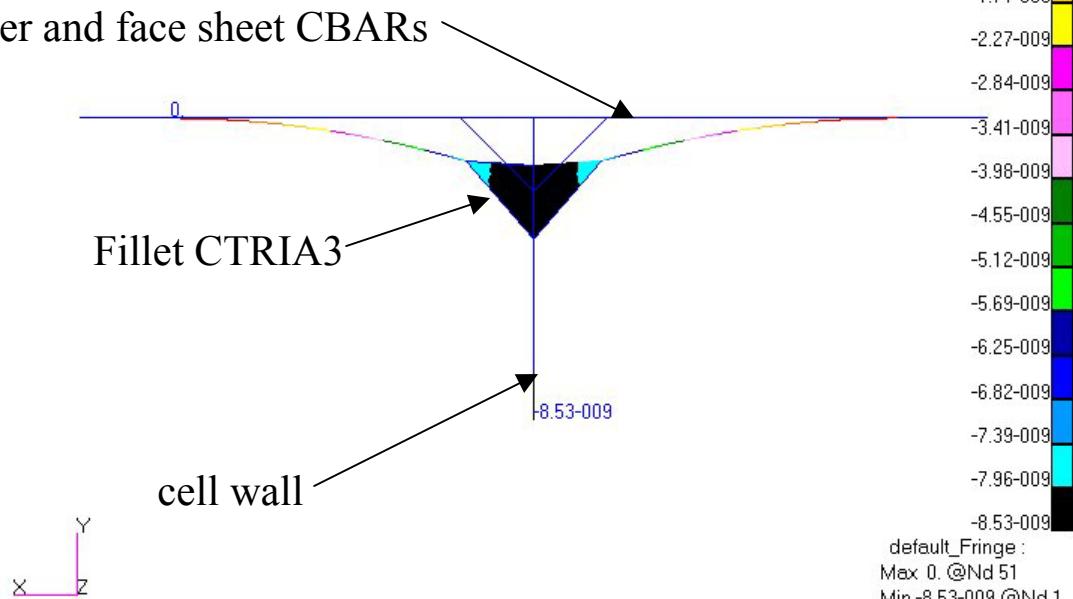
# Alternate Analysis Method

MSC.Patran 2000 r2 22-Apr-02 13:42:16

Fringe: Default, Static Subcase\_5: Displacements, Translational-(NON-LAYERED) (YY)

Deform: Default, Static Subcase\_5: Displacements, Translational

Surface layer and face sheet CBARs



If this model were extended in and out of the page the CBARs would become plates and the CTRIA3s would be CPENTAs (wedge elements). This model provides some evidence that a hybrid model will predict print-thru.

Hybrid cross-section model parameters: surface layer CTE = 0.513 ppm/K,  
surface layer thickness = 12.7 microns



# Conclusions

- Print-thru can be predicted with a mirror model represented with plate elements.
- SBMD print-thru is produced by the fillets between the facesheet and cell walls coupled with a thin mirror surface layer with a larger CTE and the mirror subjected to a uniform temperature change.